



Shenzhen Tuofeng Semiconductor Technology Co., Ltd

N - CHANNEL ENHANCEMENT MODE POWER MOSFET

SGT MOS、低内阻、低结电容开关损耗小

TF130N10MG**• General Description**

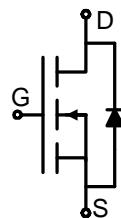
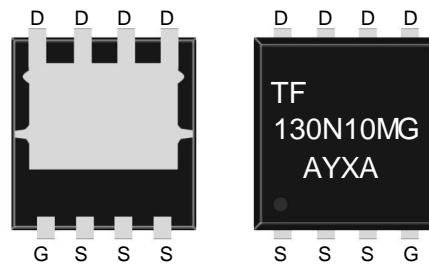
The TF130N10MG uses advanced trench technology and design to provide excellent RDS(ON) with low gate charge. It can be used in a wide variety of applications.

• Features

- Advance device construction
- Low $R_{DS(ON)}$ to minimize conduction loss
- Low Gate Charge for fast switching
- Low Thermal resistance

• Application

- Synchronous Rectification for AC-DC/DC-DC converter
- Power Tools

• Product Summary $V_{DS} = 100V \quad I_D = 40A$ $R_{DS(ON)(10V \text{ typ})} = 13m\Omega$ $R_{DS(ON)(4.5V \text{ typ})} = 16m\Omega$ **PDFN 3.3x3.3-8L****• Package Marking and Ordering Information:**

| | |
|---------------------|---|
| Part NO. | TF130N10MG |
| Marking1 | 130N10MG |
| Marking2 | TF:tuofeng; AA:device code; Y:year code; X:Week |
| Basic ordering unit | 5000 / PCS |

• Absolute Maximum Ratings ($T_C = 25^\circ C$)

| Parameter | Symbol | Rating | Unit |
|-----------------------------------|---------------------------|------------|------------|
| Drain-Source Voltage | V_{DS} | 100 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | V |
| Continuous Drain Current | $I_D @ T_C = 25^\circ C$ | 40 | A |
| | $I_D @ T_C = 75^\circ C$ | 28 | A |
| | $I_D @ T_C = 100^\circ C$ | 18 | A |
| Pulsed Drain Current ^① | I_{DM} | 160 | A |
| Total Power Dissipation | $P_D @ T_C = 25^\circ C$ | 48 | W |
| Total Power Dissipation | $P_D @ T_A = 25^\circ C$ | 1.0 | W |
| Operating Junction Temperature | T_J | -55 to 150 | $^\circ C$ |
| Storage Temperature | T_{STG} | -55 to 150 | $^\circ C$ |
| Single Pulse Avalanche Energy | E_{AS} | 50 | mJ |



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| Parameter | Symbol | Min. | Typ. | Max. | Unit |
|--|-------------------|------|------|------|-------|
| Thermal resistance, junction - case | R _{thJC} | - | - | 6.0 | ° C/W |
| Thermal resistance, junction - ambient | R _{thJA} | - | - | 60 | ° C/W |
| Soldering temperature, wavesoldering for 8 s | T _{sold} | - | - | 260 | ° C |

•Electronic Characteristics

| Parameter | Symbol | Condition | Min. | Typ | Max. | Unit |
|-----------------------------------|---------------------|--|------|-----|------|------|
| Drain-Source Breakdown Voltage | BV _{DSS} | V _{GS} = 0V, I _D = 250uA | 100 | - | - | V |
| Gate Threshold Voltage | V _{GS(TH)} | V _{GS} = V _{DS} , I _D = 250uA | 1.2 | 1.7 | 2.5 | V |
| Drain-Source Leakage Current | I _{DSS} | V _{DS} =100 V _{GS} = 0V | - | - | 1.0 | uA |
| Gate- Source Leakage Current | I _{GSS} | V _{GS} =±20V , V _{DS} = 0V | - | - | ±100 | nA |
| Static Drain-source On Resistance | R _{DS(ON)} | V _{GS} =10V, I _D =15A | - | 13 | 17 | mΩ |
| | | V _{GS} =4.5V, I _D =10A | - | 16 | 24 | mΩ |
| Forward Transconductance | g _{FS} | V _{DS} = 25V, I _D =15A | - | 15 | - | S |
| Source-drain voltage | V _{SD} | I _S =15A | - | - | 1.20 | V |

•Electronic Characteristics

| Parameter | Symbol | Condition | Min. | Typ | Max. | Unit |
|------------------------------|------------------|----------------------------------|------|------|------|------|
| Input capacitance | C _{iss} | f = 1MHz V _{DS} =50V | - | 1130 | - | pF |
| Output capacitance | C _{oss} | | - | 430 | - | |
| Reverse transfer capacitance | C _{rss} | | - | 5.8 | - | |

•Gate Charge characteristics(T_a = 25°C)

| Parameter | Symbol | Condition | Min. | Typ | Max. | Unit |
|----------------------|-----------------|--|------|------|------|------|
| Total gate charge | Q _g | V _{DD} = 50V I _D = 10A V _{GS} = 10V | - | 15.5 | - | nC |
| Gate - Source charge | Q _{gs} | | - | 4.0 | - | |
| Gate - Drain charge | Q _{gd} | | - | 1.9 | - | |

Note: ① Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2% ;



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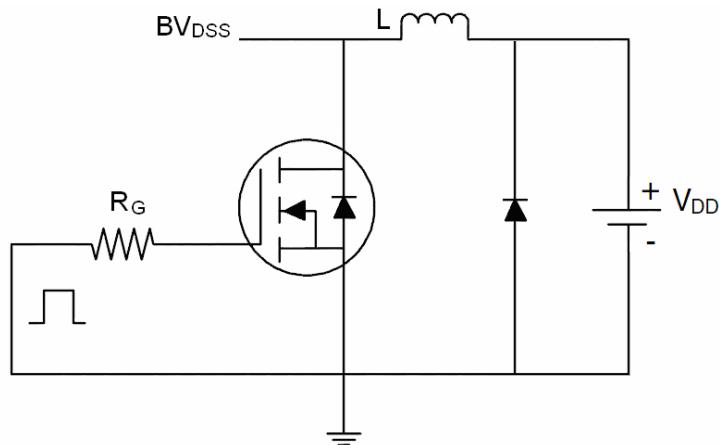
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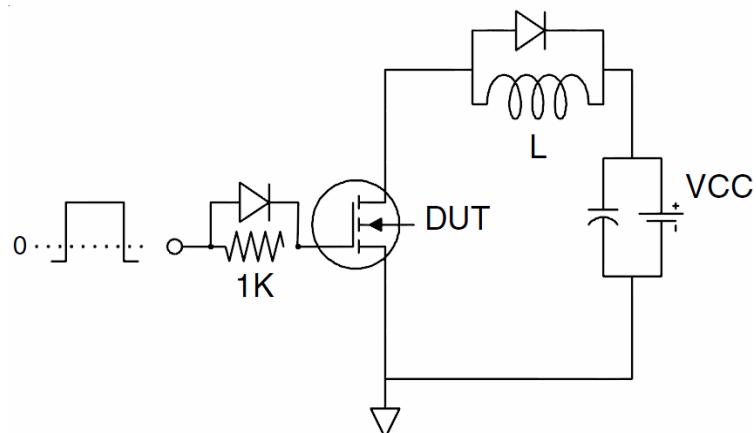
TF130N10MG

Test Circuit

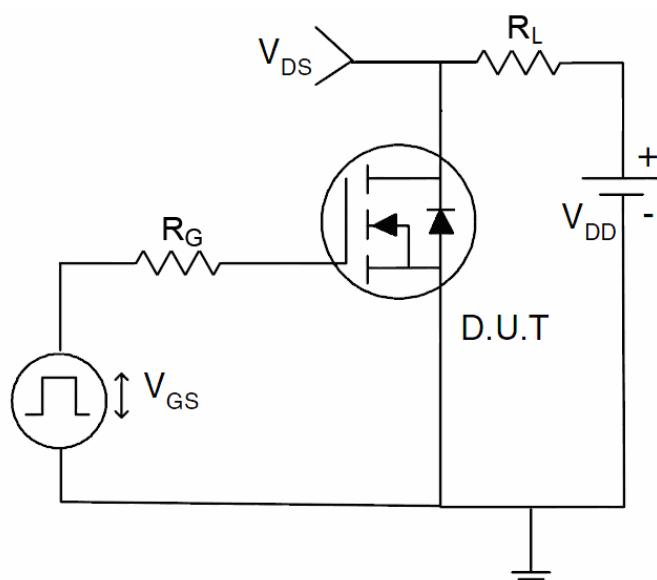
1) E_{AS} test Circuit



2) Gate charge test Circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics

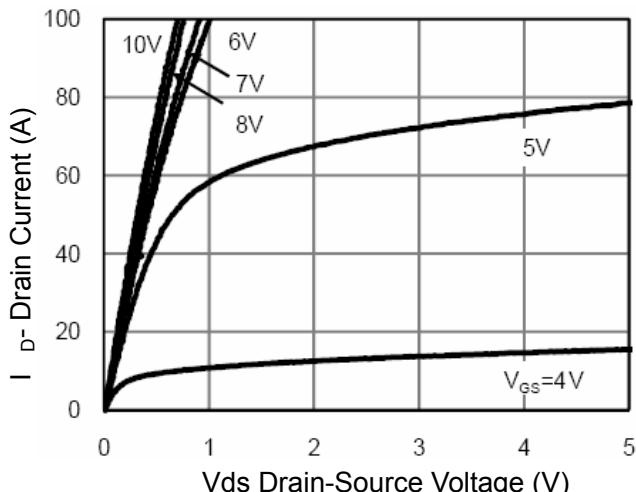


Figure 1 Output Characteristics

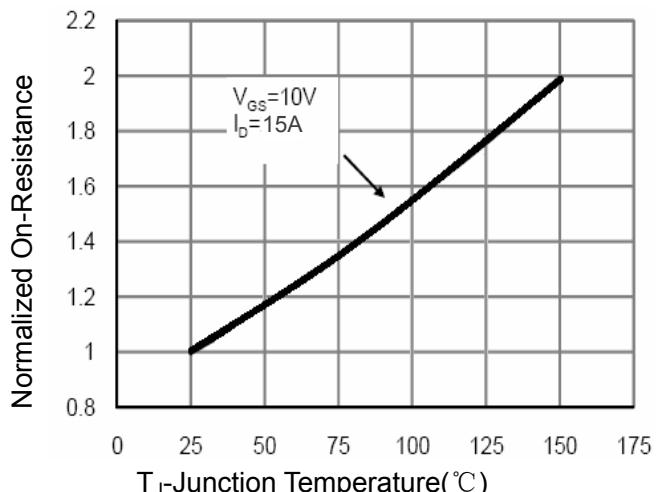


Figure 4 Rdson-JunctionTemperature

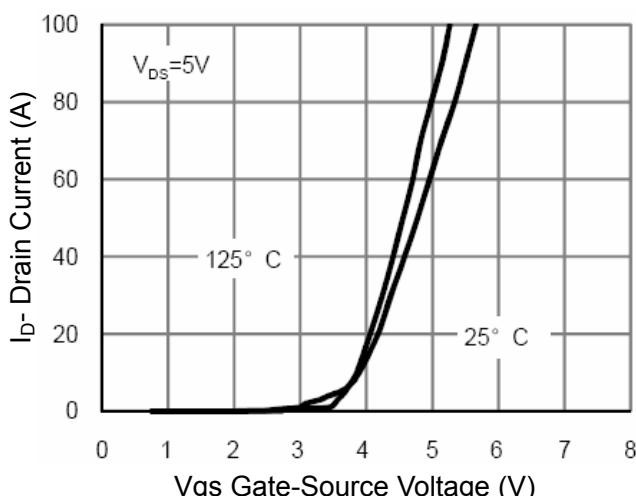


Figure 2 Transfer Characteristics

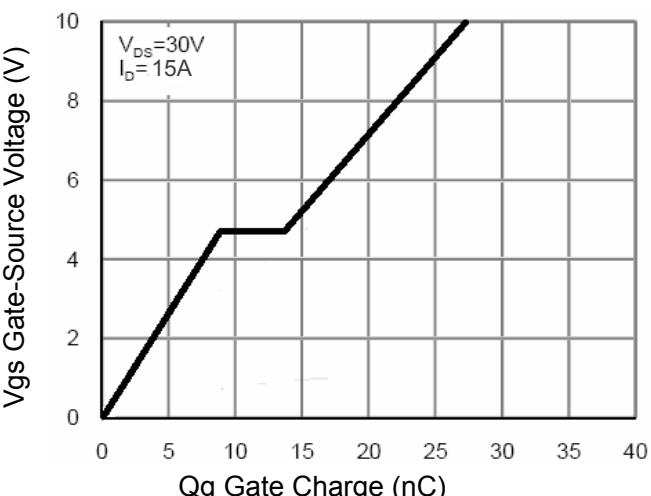


Figure 5 Gate Charge

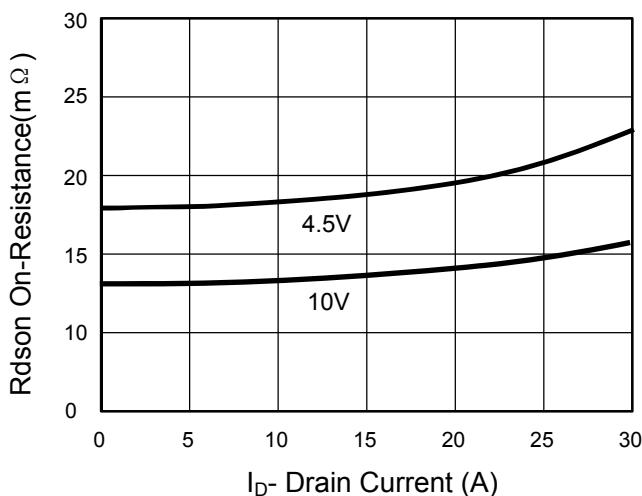


Figure 3 Rdson- Drain Current

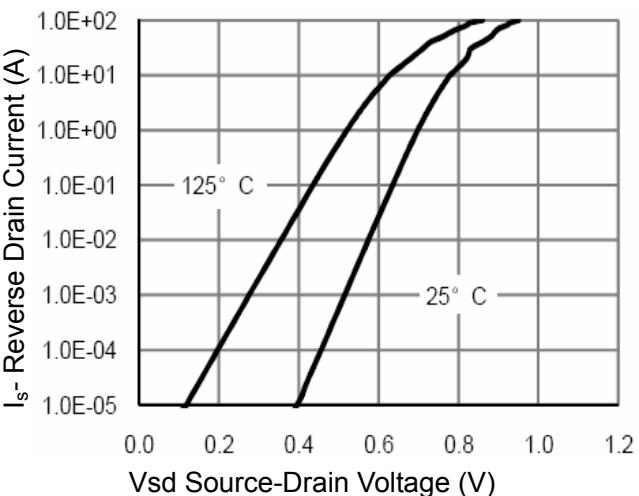


Figure 6 Source- Drain Diode Forward

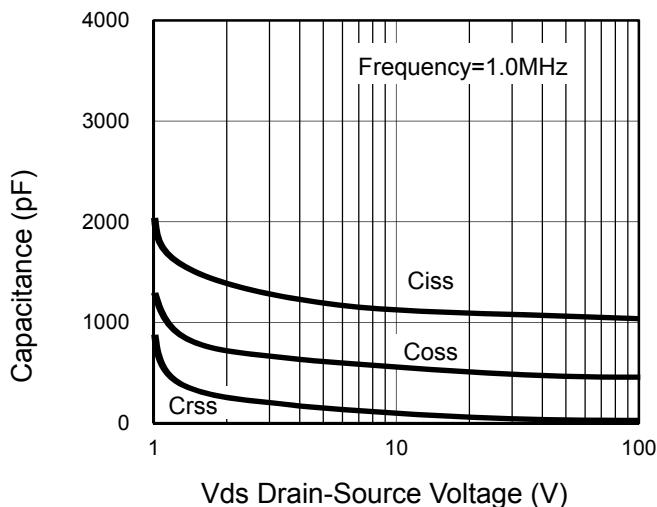


Figure 7 Capacitance vs Vds

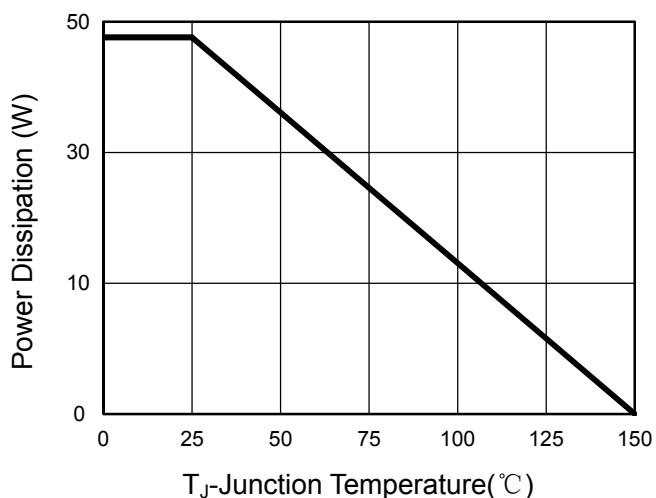


Figure 9 Power De-rating

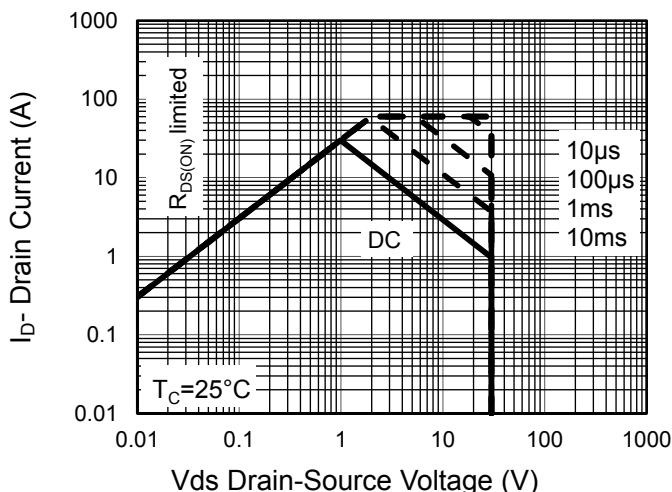


Figure 8 Safe Operation Area

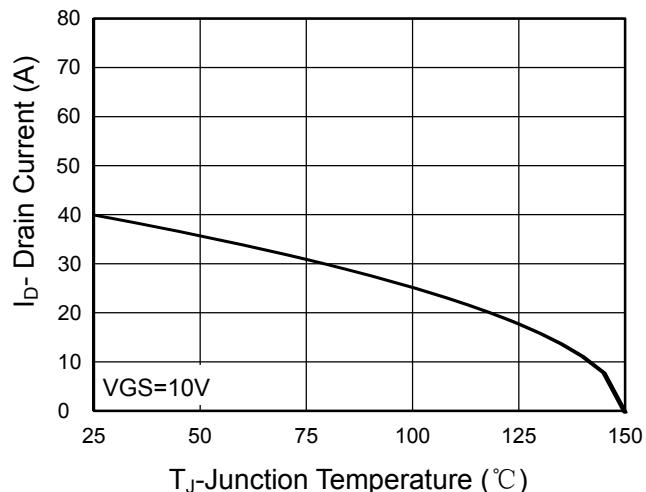


Figure 10 Current De-rating

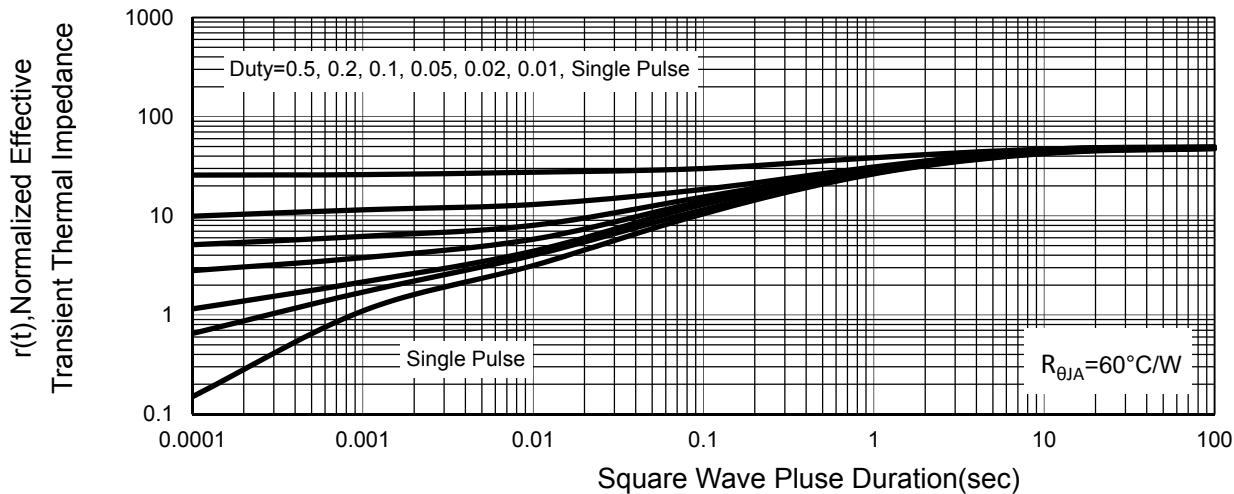
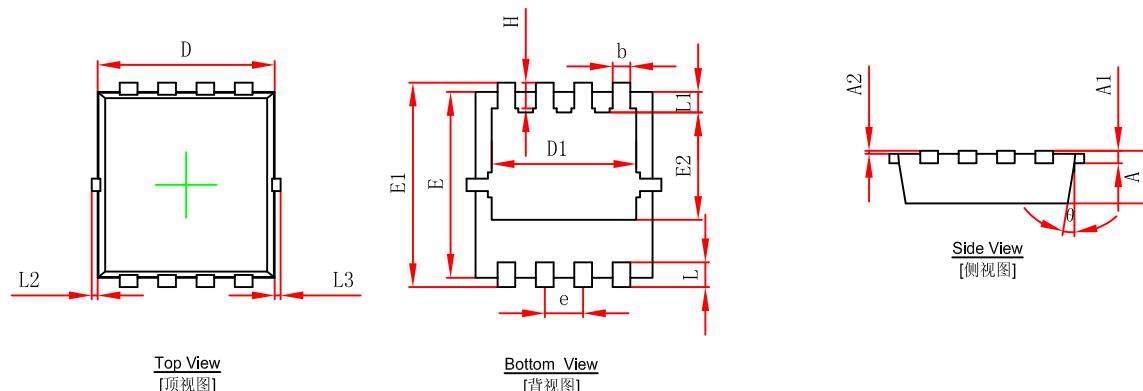


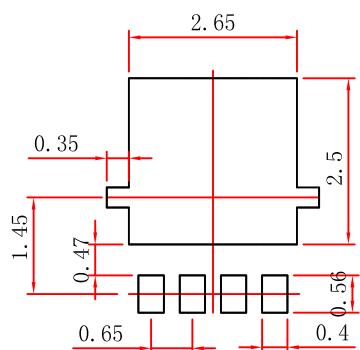
Figure 11 Normalized Maximum Transient Thermal Impedance

PDFN3.3x3.3-8L Package Outline Dimensions



| Symbol | Dimensions In Millimeters | | Dimensions In Inches | |
|--------|---------------------------|-------|----------------------|-------|
| | Min. | Max. | Min. | Max. |
| A | 0.650 | 0.850 | 0.026 | 0.033 |
| A1 | 0.152 REF. | | 0.006 REF. | |
| A2 | 0~0.05 | | 0~0.002 | |
| D | 2.900 | 3.100 | 0.114 | 0.122 |
| D1 | 2.300 | 2.600 | 0.091 | 0.102 |
| E | 2.900 | 3.100 | 0.114 | 0.122 |
| E1 | 3.150 | 3.450 | 0.124 | 0.136 |
| E2 | 1.535 | 1.935 | 0.060 | 0.076 |
| b | 0.200 | 0.400 | 0.008 | 0.016 |
| e | 0.550 | 0.750 | 0.022 | 0.030 |
| L | 0.300 | 0.500 | 0.012 | 0.020 |
| L1 | 0.180 | 0.480 | 0.007 | 0.019 |
| L2 | 0~0.100 | | 0~0.004 | |
| L3 | 0~0.100 | | 0~0.004 | |
| H | 0.315 | 0.515 | 0.012 | 0.020 |
| θ | 9° | 13° | 9° | 13° |

PDFN3.3x3.3-8L Suggested Pad Layout



Note:

1. Controlling dimension: in millimeters.
2. General tolerance: ± 0.05 mm.
3. The pad layout is for reference purposes only.